Kratos SRE offers clients proven expertise in precision metrology for a range of applications including space structures, optical benches, dimensional validation, and surface profiling. We offer extensive experience in designing custom precision metrology systems to meet our clients’ specialized needs. Advanced techniques include interferometer, digital image correlation, and structured light-based methods. Capability includes static dimensional assessment and distortion tracking from thermal or mechanical loading. Techniques can be applied to parts ranging from <mm to >1 meter in length.
- **Dimensional Measurement**
  - Scanning
  - Tolerance Verification
  - Acceptance Testing

- **Structure Distortion Measurement**
  - Space Structures
  - Thermal Distortion
  - Load Deformation

- **Structured Light**
  - Defect Visualization
  - Surface Mapping
  - Dimensional Profiling